Process And Temperature Tracking Bias Circuits For Realization Of Pt-Invariant Quantities In Analog Circuits

## Title:

The present invention discloses a a process and temperature tracking bias circuits for realization of PT-invariant quantities in analog circuits. A process and temperature tracing bias circuit is designed for making a constant resistance. On-chip resistances like RS- Nwel varies by a factor of  $\pm$  20% at one particular temperature. The proposed bias technique which varies by  $\pm$  7.4% with process,  $\pm$  1.5% with temperature from 0°C to 100°C. resistance of a nmos transistor biased in linear region by a factor of  $\pm$  37% with process.

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